


<b>Search Notes</b>  	<b>Application/Control No.</b>  10598615	<b>Applicant(s)/Patent Under Reexamination</b>  WATANABE ET AL.
	<b>Examiner</b>  John Pak	<b>Art Unit</b>  1616

SEARCHED			
Class	Subclass	Date	Examiner
514	229.2, 341, 357, 365, 471	1/2011	JP

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor names searched	1/2011	JP
STN Online, Files HCAPLUS, WPIDS, CABA. See printout.	1/2011	JP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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